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Jagielski, J., H. Viguier, J.P. Frontier, P. Trouslard, B. Kopcewicz, M. Kopcewicz and L. Thomé, PIXE study of atmospheric aerosols in mountain region of Poland 118 (1996) 388
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Knözinger, H., see Linsmeier, Ch. 118 (1996) 533
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Kozanecki, A., J. Kaczanowski, B.J. Sealy and W.P. Gillin, Analysis of strain in ultra-thin $GaAs/In_{0.2}Ga_{0.8}As/GaAs$ single quantum well structures by channeling technique 118 (1996) 640
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Li, Y., J.A. Kilner, T.J. Tate and P.G. Quincey, Evolution of the implanted ^{18}O concentration distribution in a $YBa_2Cu_3O_{7-\delta}$ film during rapid thermal annealing 118 (1996) 670
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McIntyre Jr., L.C., J.A. Leavitt, M.D. Ashbaugh, J. Borgardt, E. Andrade, J. Rickards and A. Oliver, Cross section measurements for the (^3He, p) nuclear reaction on B and N between 2 and 4 MeV 118 (1996) 219
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Piel, N., W.H. Schulte, M. Berheide, H.W. Becker, L. Borucki, C. Grama, M. Mehrhoff and C. Rolfs, Efficient γ-ray detection in ion beam analysis 118 (1996) 186
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Rajta, I., I. Borbély-Kiss, Gy. Mórik, L. Bartha, E. Koltay, Á.Z. Kiss and Gy. Szőőr, The Debrecen scanning proton microprobe facility and its applications to geological samples 118 (1996) 437
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Šandrik, R., M. Jergel, V. Štrbik, K. Nakamura, A. Ishii, I. Orlic, S.M. Tang and F. Watt, Analysis of stoichiometry of high-T_c superconducting films by RBS and PIXE methods 118 (1996) 602
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Vickridge, I.C., I.W.M. Brown, T.C. Ekström and W.J. Trompetter, Ion beam analysis of sialon ceramics . . . 118 (1996) 608
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Watamori, M., K. Oura, T. Hirao and K. Sasabe, Backscattering analysis of thin SiO_2 films on Si using $^{16}O(\alpha,\alpha)^{16}O$ 3.045 MeV resonance . . . 118 (1996) 228
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